

Linear IC

6-Channel 8-BIT A/D Converter

MB4053

■ DESCRIPTION

The Fujitsu MB4053 is 6-channel, 8-bit, single-slope A/D converter subsystem designed to be used in a microprocessor based data control system.

The MB4053 is single monolithic bipolar IC providing a 1 of 8 address decoder, 8-channel analog multiplier, sample and hold, constant current generator, ramp integrator and comparator in a 16-pin package.

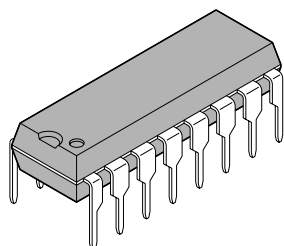
This A/D converter subsystems are suitable for a wide range of applications. The resolution required by an application can be obtained by arbitrarily selecting a suitable integration time. Also zero offset and full-scale error corrections can be made automatically (auto-zero and auto-calibration) to minimize conversion error.

■ FEATURES

- Microprocessor compatible
- Digital input/output: TTL compatible
- Zero offset and full-scale error correction capability
- Ratiometric conversion capability
- Available in 16-pin DIP and Flat Package
- Compatible with MC 14443 and μ A9708 (DIP package)
- Single power supply: +4.75 V to +15 V
- Excellent linearity: $\pm 0.2\%$ max. error
- Fast conversion time: 300 μ s/ch typ.
- Analog input voltage: 0 V to $V_{CC} - 2$ V (5.25 V max.)
- Power Dissipation: 25 mW typ. at $V_{CC} = 5$ V

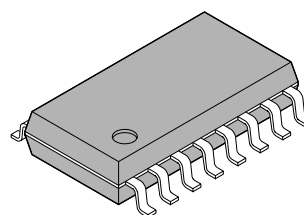
■ PACKAGES

16-pin Plastic DIP



(DIP-16P-M04)

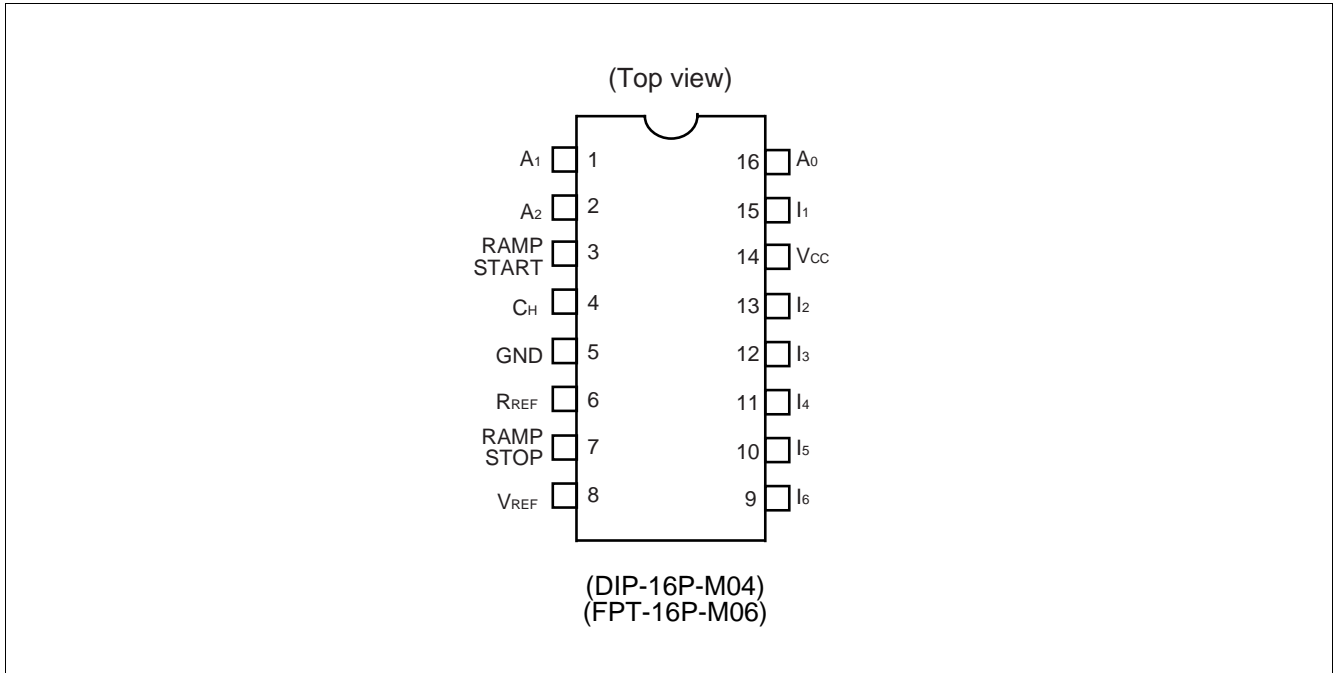
16-pin Plastic SOP



(FPT-16P-M06)

MB4053

■ PIN ASSIGNMENT

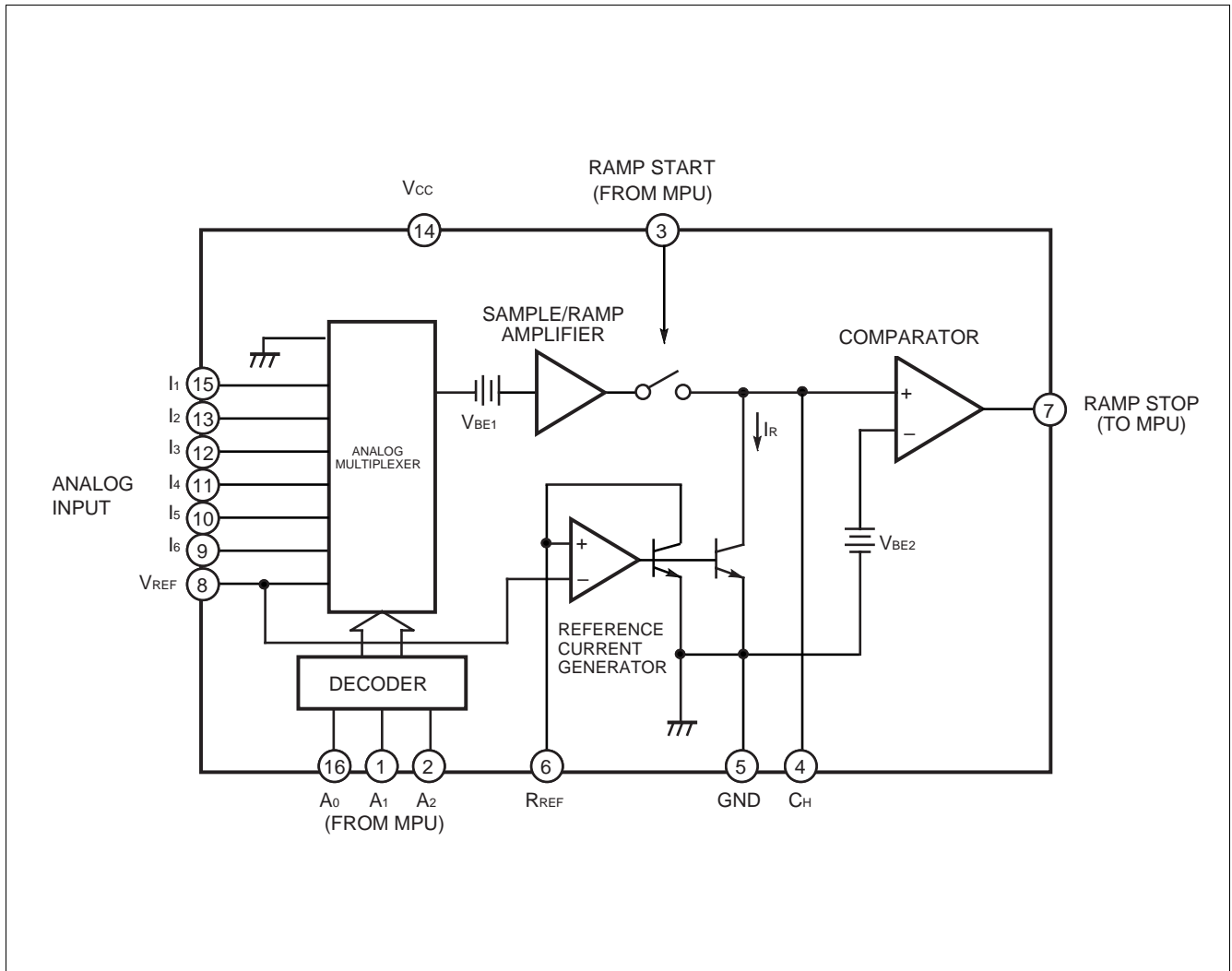


■ PIN DESCRIPTION

Pin no.	Pin name	Symbol	Function
9 to 13 15	Analog input	I ₁ thru I ₆	Analog inputs for the six channels. One of the 6 is selected by a specific bit pattern on A ₀ to A ₂ .
16 1 2	Channel selection input	A ₀ A ₁ A ₂	Input for selecting an analog input channel. Either GND, one of channels I ₁ to I ₆ or V _{REF} is selected by a specific bit pattern on the 3 inputs.
3	RAMP START signal input	RAMP START	A/D conversion start signal input. RAMP START (1 → 0) Ramp time start signal input. RAMP START (0 → 1)
7	RAMP STOP signal output	RAMP STOP	Indicates that C _H is charged over comparator reference voltage V _{BE2} . RAMP STOP (0 → 1) A/D conversion end signal (C _H discharged to comparator reference voltage). RAMP STOP (0 → 1)
4	Ramp capacitor pin	C _H	Pin for externally connecting the ramp capacitor. The value of C _H in conjunction with V _{REF} and R _{REF} establishes the ramp time.
8	Reference voltage supply pin	V _{REF}	Reference voltage supply pin. This is the reference voltage source for determining the discharge current and the analog reference voltage for full-scale factor correction. When the channel selection input is set 111, this pin is selected for channel conversion. The full-scale factor is corrected using the conversion results. The voltage at this pin must be set to (GND + 2 V) to (V _{CC} – 2 V) and 5.25 V or less.
6	Reference resistance pin	R _{REF}	Pin for external reference resistance for setting the discharge current. The external resistance is connected between the power source pin (V _{CC}) and the reference resistance pin (R _{REF}). The discharge current is, then, $I_R = (V_{CC} - V_{REF})/R_{REF}$.
14	Power supply	V _{CC}	Power supply pin
5	Ground	GND	Ground pin This pin is grounded. When the channel selection input is set to 000, this terminal is selected for channel conversion. The zero offset is corrected using the conversion results.

MB4053

■ BLOCK DIAGRAM



■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rating		Unit	
		Min.	Max.		
Power supply voltage	V_{CC}	—	18	V	
Digital input voltage	V_{IND}	-0.5	+30	V	
Digital output voltage when off	V_{OH}	-0.5	+18	V	
Analog input voltage	V_{INA}	-0.5	+30	V	
Output current	I_o	—	10	mA	
Storage temperature	Ceramic	T_{stg}	-55	+150	°C
	Plastic		-55	+125	°C

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Value			Unit
		Min.	Typ.	Max.	
Power supply voltage	V_{CC}	4.75	5.0	15	V
Reference voltage*	V_{REF}	2.0	—	5.25	V
Ramp capacity	C_H	300	—	—	pF
Reference current	I_R	12	—	50	μA
Analog input voltage	V_{IA}	0	—	V_{REF}	V
Output current	I_o	—	—	1.6	mA
Operating temperature	T_a	-40	—	+85	°C

* : $2\text{ V} \leq V_{REF} \leq V_{CC} - 2\text{ V}$

WARNING: Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representative beforehand.

MB4053

■ ELECTRICAL CHARACTERISTIC

(V_{CC} = 4.75 V to 15 V, T_a = -40°C to +85°C)

Parameter	Symbol	Value			Unit	Remarks
		Min.	Typ.	Max.		
Conversion error	E _A	—	±0.2	±0.3	%	*1
Linearity error	E _R	—	±0.08	±0.2	%	*2
Analog input current	I _B	—	-50	-250	nA	
Crosstalk between any two channels	V _{CR}	60	—	—	dB	*3
Multiplexer input offset voltage	V _{OSM}	—	2.0	4.0	mV	
Conversion time	t _c	—	296	350	μs/ch	See "■MEASURMENT CIRCUIT" Analog input: 0 thru V _{REF} C _H = 3300 pF, I _R = 50 μA
Acquisition time	t _A	—	20	40	μs	See "■MEASURMENT CIRCUIT" C _H = 1000 pF*4
Acquisition current	I _A	150	—	—	μA	
Ramp start delay time	t _o	—	100	—	ns	
Multiplexer address time	t _M	—	1	—	μs	
Digital high level input voltage	V _{IH}	2.0	—	—	V	
Digital low level input voltage	V _{IL}	—	—	0.8	V	
Digital low level input current	I _{IL}	—	-5	-15	μA	V _{IL} = 0.4 V
Digital high level input current	I _{IH}	—	—	1	μA	V _{IH} = 5.5 V
High level output current	I _{OH}	—	—	10	μA	V _{OH} = 15 V
Low level output voltage	V _{OL}	—	—	0.4	V	I _{OL} = 1.6 mA
Power supply current	I _{CC}	—	5	10	mA	

A minus sign (-) prefixing a current value indicates that the current flows from the IC to the external circuit.

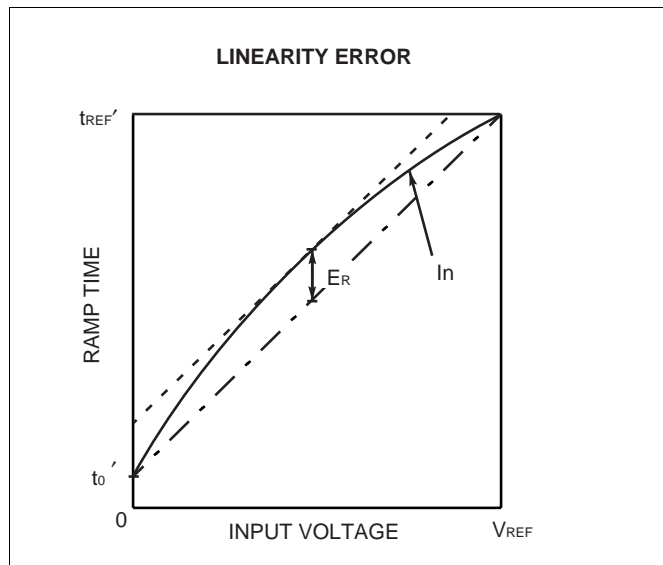
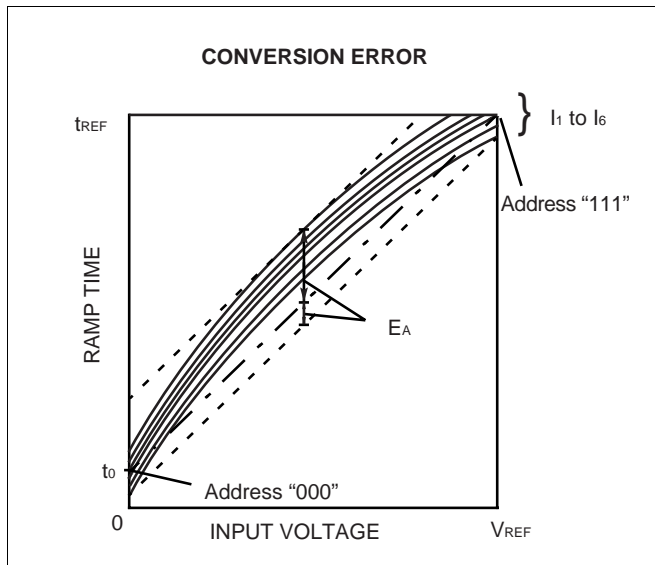
*1: Conversion error: For all channels, deviation from a straight line between two points obtained by channel addresses 000 (0 scale) and 111 (full scale).

*2: Linearity error; Deviation from a straight line between the 0 and full scale points for each channel.

*3: Crosstalk between channels: Voltage change V_{CH} of C_H terminal occurring when an input voltage of a channel is changed by ΔV₁ while another channel is already charged (RAMP START = 0).

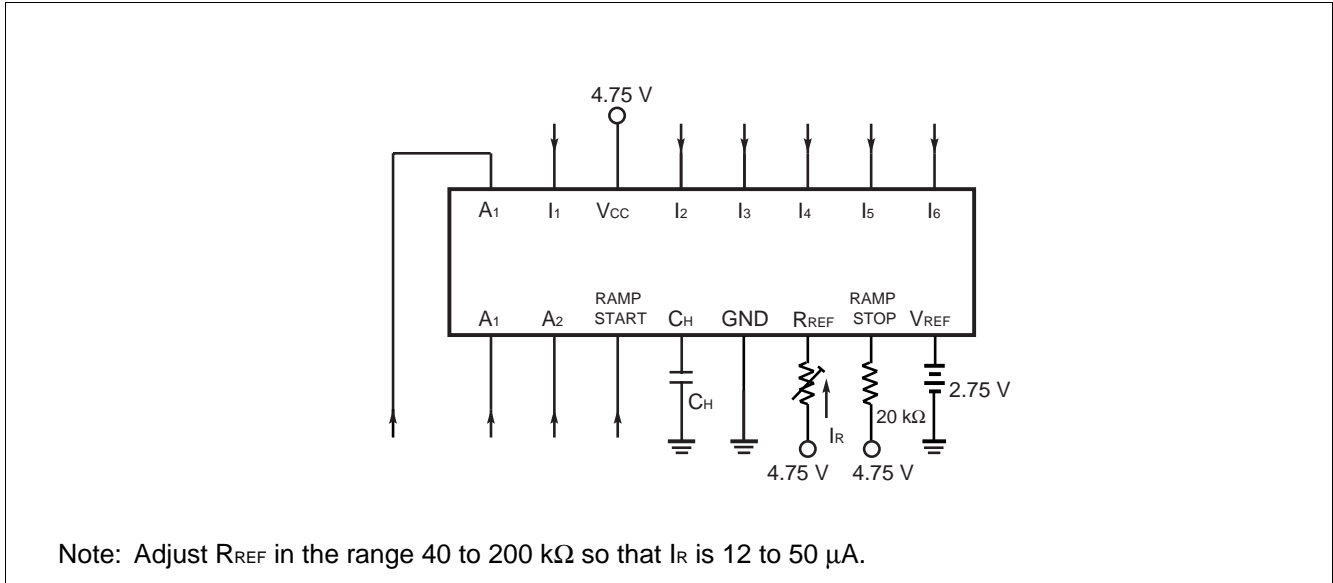
This calculated by $20 \log \frac{\Delta V_{CH}}{\Delta V_1}$

*4: Acquisition time: Sum of multiplexer delay time, RAMP START delay time, and time required to charge the selected input voltage to the ramp capacitor.

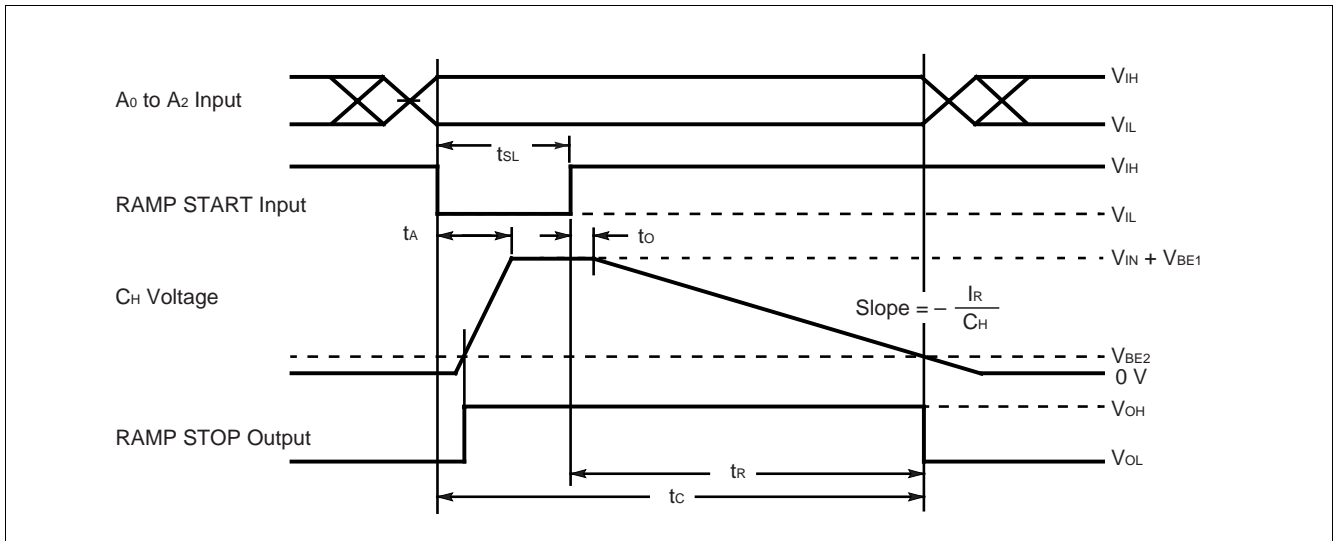


MB4053

MEASUREMENT CIRCUIT



DIAGRAM

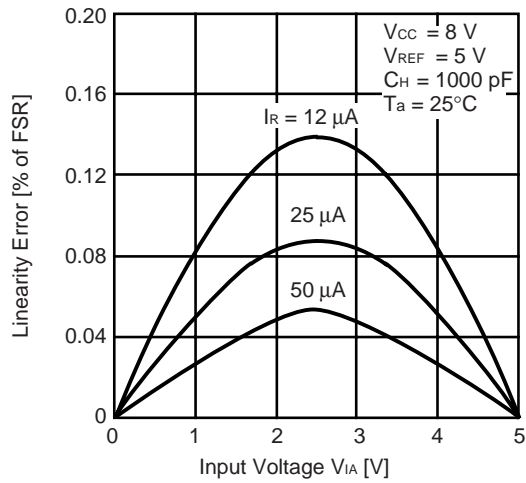


CHANNEL SELECTION

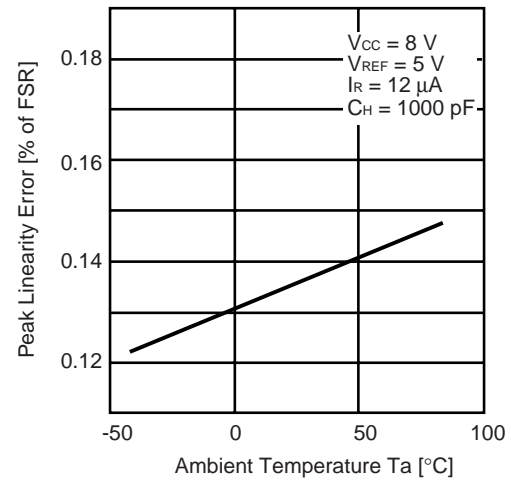
Input address line			Selected analog input
A ₂	A ₁	A ₀	
0	0	0	GND
0	0	1	I ₁
0	1	0	I ₂
0	1	1	I ₃
1	0	0	I ₄
1	0	1	I ₅
1	1	0	I ₆
1	1	1	V _{REF}

■ TYPICAL CHARACTERISTICS

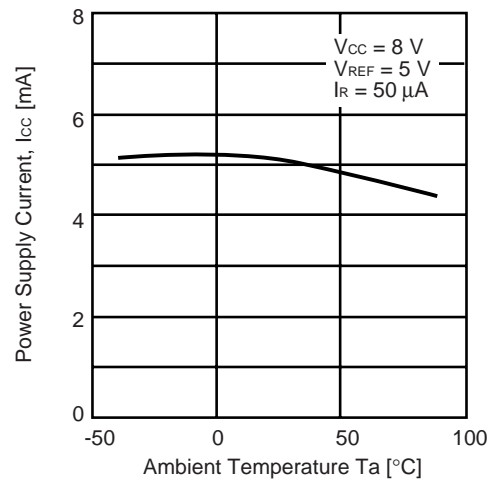
LINEARITY ERROR vs INPUT VOLTAGE



PEAK LINEARITY ERROR vs AMBIENT TEMPERATURE T_a



SUPPLY CURRENT vs AMBIENT TEMPERATURE



■ OPERATION DESCRIPTION

Refer to BLOCK DIAGRAM, and DIAGRAM. Address inputs A_0 to A_2 are used to select the analog input to be converted, (one of the six analog inputs I_1 to I_6). The RAMP START input is switched from a logic 1 to a logic zero. This causes the external ramp capacitor C_H to charge at a fixed rate. (Note 1) until it reaches the sum of the selected analog input voltage and a constant offset voltage V_{BE1} . The RAMP STOP output (open-collector switches from a logic 0 to logic 1 when the voltage on C_H reaches the comparator reference voltage V_{BE2} . The RAMP START input is switched back to a logic 1 after C_H is completely charged. This disconnects the analog input from C_H and allows it to be gin discharging at a fixed rate (Note 2). When the voltage on C_H reaches the comparator reference voltage V_{BE2} the RAMP STOP output switches back to a logic 0. This completes a conversion cycle for 1 channel.

The time between the RAMP START input switching ($0 \rightarrow 1$) and RAMP STOP output switching ($1 \rightarrow 0$) is the RAMP TIME t_R . This would be directly proportional to the analog input voltage for the ideal situation where there was no comparator switching level error, leakage, switching delay times or effect of the impedance of the internal reference current source. t_R can be calculated for the ideal case as follows:

$$t_R = V_{IN} \times \frac{C_H}{I_R}$$

Where: V_{IN} = Analog input voltage to be measured

C_H = External ramp capacitor

$$I_R = \frac{V_{CC} - V_{REF}}{R_{REF}}$$

This ramp time is converted to a digital representation by counting t_R with the microprocessor. If a small error can be tolerated, the A/D conversion software can be reduced and the conversion time minimized by omitting corrections.

Notes:

$$*1 \text{ Charge slope} = \frac{I_A - I_R}{C_H} \geq \frac{150 \mu A - I_R}{C_H}$$

Where: I_A is the acquisition current whose value is determined from the circuit constant in the IC.

$$*2 \text{ Discharge slope} = - \frac{I_R}{C_H}$$

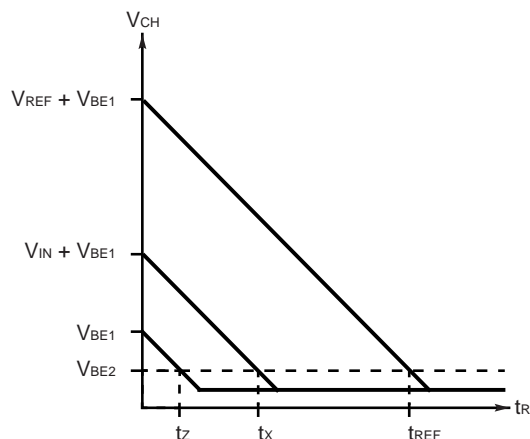
■ ZERO OFFSET AND FULL-SCALE FACTOR CORRECTIONS

High precision conversions can be achieved by correcting for zero offset and full scale factor as follows:

The channel select address (A_0 to A_2) is set to 000. Ground (GND) is selected (internally) as the analog input and converted. This results in ramp time t_r . Next the address is set to 111. V_{REF} is selected (internally) and converted. This results in ramp time, t_{REF} . Finally the desired analog input (one of I_1 to I_6) is selected and converted. This results in ramp time t_x . This conversion sequence is arbitrary and the GND and V_{REF} conversions are not needed each time a channel is converted but only as required for calibration. The relationships between the inputs and ramp times are shown below.

$$\begin{aligned} (V_{BE1})_C &= t_z \\ (V_{REF} + V_{BE1})_C &= t_{REF} \\ (V_{IN} + V_{BE1})_C &= t_x \\ (V_{REF})_C &= t_{REF} - t_z \\ (V_{IN})_C &= t_x - t_z \end{aligned}$$

$$\frac{(V_{IN})_C}{(V_{REF})_C} = \frac{t_x - t_z}{t_{REF} - t_z}$$



The conversion error can then be minimized by using the above results in the expression below to calculate the corrected analog input voltage.

$$(V_{IN})_C = (V_{REF})_C \times \frac{t_x - t_z}{t_{REF} - t_z}$$

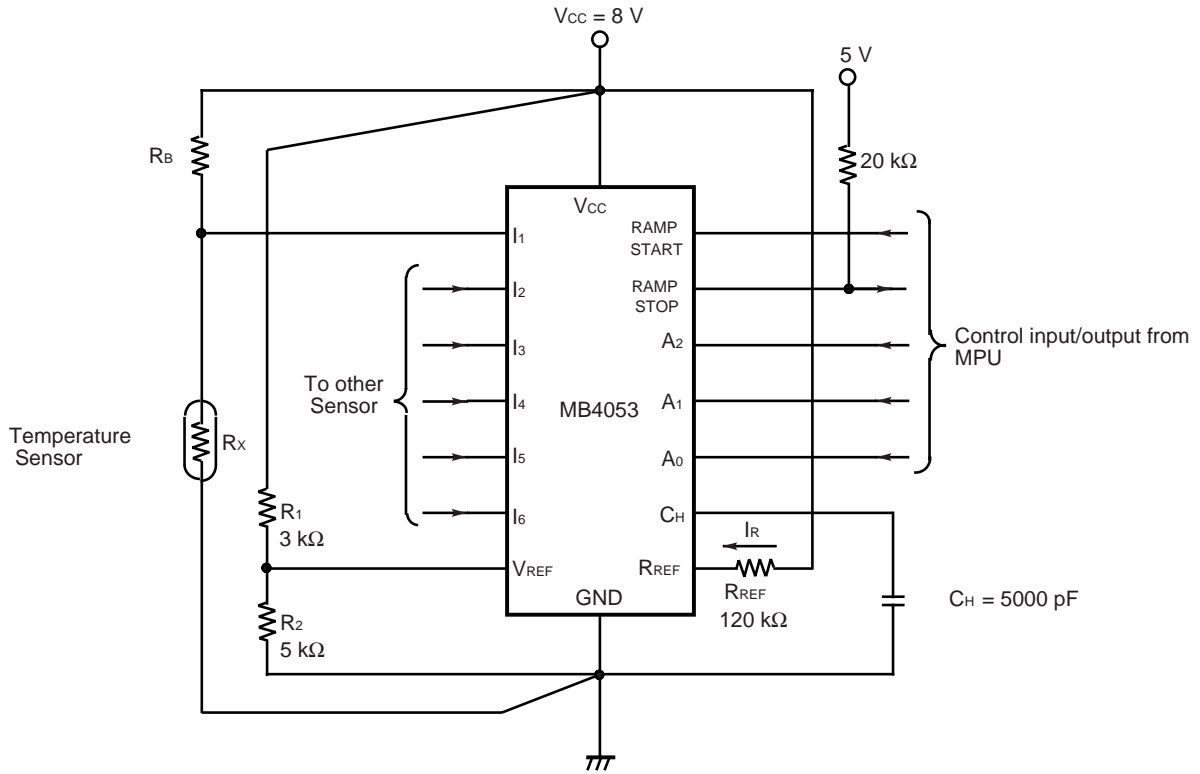
Where: V_{IN} = Analog input voltage to be measured
 V_{REF} = Reference voltage
 V_{BE1} = Shift voltage in sample/ramp amplifier
 V_{BE2} = Threshold voltage of comparator
 V_{CH} = C_H voltage

The GND and V_{REF} conversion sequence is arbitrary, the GND and V_{REF} conversions not being needed each time a channel (I_1 to I_6) is converted.

MB4053

APPLICATION EXAMPLES

Examples of analog voltage (0 to 5 V) A/D conversion with 10-bit resolution are shown in “PEAK LINEARITY ERROR vs AMBIENT TEMPERATURE T_a ” and “SUPPLY CURRENT vs AMBIENT TEMPERATURE”.



$$\text{Reference Voltage: } V_{REF} = \frac{R_2}{R_1 + R_2} V_{CC} \dots\dots\dots 7-1$$

$$\text{Ramp Current: } I_R = \frac{R_1}{R_1 + R_2} \cdot \frac{1}{R_{REF}} V_{CC} \dots\dots\dots 7-2$$

$$\text{Input Voltage: } V_{IN} = \frac{R_X}{R_X + R_B} \cdot V_{CC} \dots\dots\dots 7-3$$

$$\begin{aligned} \text{Ramp Time: } t_r &\cong V_{IN} \cdot \frac{C_H}{I_R} \\ &= \frac{R_X}{R_X + R_B} \cdot \left(1 + \frac{R_2}{R_1}\right) \cdot C_H \cdot R_{REF} \dots\dots\dots 7-4 \end{aligned}$$

$$V_{REF} = \frac{5 \text{ k}\Omega}{3 \text{ k}\Omega + 5 \text{ k}\Omega} \times 8 \text{ V} = 5 \text{ V}$$

$$I_R = \frac{V_{CC} - V_{REF}}{R_{REF}} = \frac{8 \text{ V} - 5 \text{ V}}{120 \text{ k}\Omega} = 25 \mu\text{A}$$

$$t_{SL} \geq \frac{C_H \times V_{REF}}{I_{A(\min)} - I_R} = \frac{5000 \text{ pF} \times (5 \text{ V} + 0.7 \text{ V})}{150 \mu\text{A} - 25 \mu\text{A}} = 228 \mu\text{s}$$

$$t_{r_{\max}} \cong \frac{C_H \times V_{REF}}{I_R} = \frac{5000 \text{ pF} \times 5 \text{ V}}{25 \mu\text{A}} = 1000 \mu\text{s}$$

If the ramp time is counted with a 1 MHz clock, the following resolution is obtained.

$$\frac{1000 \mu\text{s}}{1 \mu\text{s}} = 1000 \cong 2^{10}$$

As shown in this example, the voltage output of the sensor is proportional to V_{CC} (Eq. 7-3) and V_{REF} is also proportional to V_{CC} (Eq. 7-1), the sensor output conversion results (Eq. 7-4) are not influenced by power supply voltage fluctuation. Such a conversion is called ratio metric conversion and is effective for minimizing the effects of conversion error. Supply voltage fluctuations during discharge do result in error, however.

■ USAGE PRECAUTIONS

1. Since the impedance of the ramp capacitor pin is approximately 30 MΩ (high), a resistance must not be connected in parallel with this input. A ramp capacitor with no leakage must be used.
2. At $V_{IN} = 0$ V, t_R has a finite value.
3. Since RAMP STOP is an open collector output, an external pull-up resistor is required. (For example, when a 20 kΩ external pull-up resistor is used.)
4. All digital inputs/output are TTL compatible.
5. The time from RAMP START input switching (0 → 1) to RAMP STOP output switching (1 → 0) is ramp time t_R .
6. $t_{SL} \geq t_A (\text{max}) = \frac{C_H}{150 \mu\text{A} - I_R} \times (V_{REF} + 0.7 \text{ V})$
7. $t_R \cong \frac{C_H}{I_R} \times V_{IN}$, $t_R (\text{max}) \cong \frac{C_H}{I_R} \times V_{REF}$
8. $I_R = \frac{V_{CC} - V_{REF}}{R_{REF}}$
9. $2 \text{ V} \leq V_{REF} \leq (V_{CC} - 2 \text{ V})$ and $V_{REF} \leq 5.25 \text{ V}$
10. While analog input voltage is being sampled, channel selection signals A_0 , A_1 , and A_2 must not be changed for (t_{SL}).
11. When I_R is little, Linearity Error extends. However, Linearity Error is ± 0.2 [% of FSR] or less in $I_R (\text{min}) = 12 \mu\text{A}$.

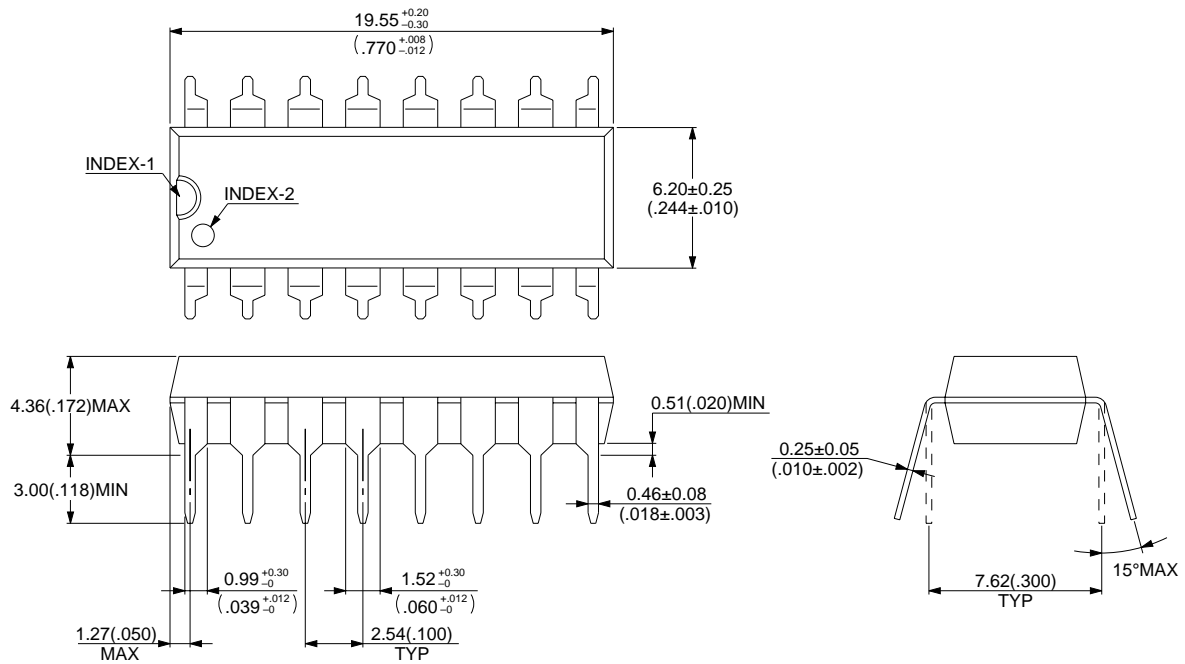
MB4053

■ ORDERING INFORMATION

Part number	Package	Remarks
MB4053M	16-pin Plastic DIP (DIP-16P-M04)	
MB4053PF	16-pin Plastic SOP (FPT-16P-M06)	

■ PACKAGE DIMENSIONS

16-pin Plastic DIP
(DIP-16P-M04)



© 1994 FUJITSU LIMITED D16033S-2C-3

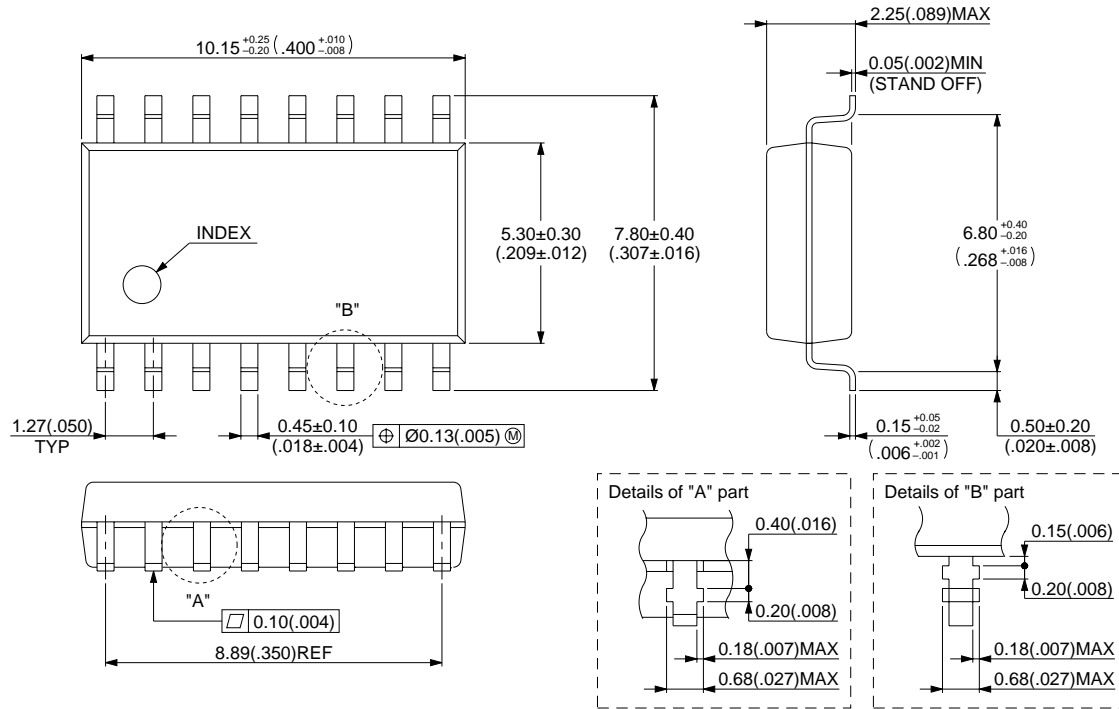
Dimensions in mm (inches)

(Continued)

MB4053

(Continued)

16-pin Plastic SOP
(FPT-16P-M06)



© 1994 FUJITSU LIMITED F16015S-2C-4

Dimensions in mm (inches)

FUJITSU LIMITED

For further information please contact:

Japan

FUJITSU LIMITED
Corporate Global Business Support Division
Electronic Devices
KAWASAKI PLANT, 4-1-1, Kamikodanaka
Nakahara-ku, Kawasaki-shi
Kanagawa 211-8588, Japan
Tel: (044) 754-3763
Fax: (044) 754-3329

<http://www.fujitsu.co.jp/>

North and South America

FUJITSU MICROELECTRONICS, INC.
Semiconductor Division
3545 North First Street
San Jose, CA 95134-1804, USA
Tel: (408) 922-9000
Fax: (408) 922-9179

Customer Response Center
Mon. - Fri.: 7 am - 5 pm (PST)
Tel: (800) 866-8608
Fax: (408) 922-9179

<http://www.fujitsumicro.com/>

Europe

FUJITSU MIKROELEKTRONIK GmbH
Am Siebenstein 6-10
D-63303 Dreieich-Buchsschlag
Germany
Tel: (06103) 690-0
Fax: (06103) 690-122

<http://www.fujitsu-edc.com/>

Asia Pacific

FUJITSU MICROELECTRONICS ASIA PTE LTD
#05-08, 151 Lorong Chuan
New Tech Park
Singapore 556741
Tel: (65) 281-0770
Fax: (65) 281-0220

<http://www.fmap.com.sg/>

F9803

© FUJITSU LIMITED Printed in Japan

All Rights Reserved.

The contents of this document are subject to change without notice. Customers are advised to consult with FUJITSU sales representatives before ordering.

The information and circuit diagrams in this document presented as examples of semiconductor device applications, and are not intended to be incorporated in devices for actual use. Also, FUJITSU is unable to assume responsibility for infringement of any patent rights or other rights of third parties arising from the use of this information or circuit diagrams.

FUJITSU semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION:

Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with FUJITSU sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

If any products described in this document represent goods or technologies subject to certain restrictions on export under the Foreign Exchange and Foreign Trade Control Law of Japan, the prior authorization by Japanese government should be required for export of those products from Japan.